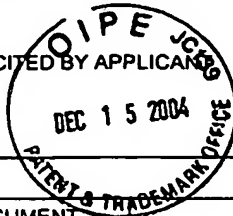


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249689US2SDIV		SERIAL NO. New DIV Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hideo ANDO, et al.			
				FILING DATE Herewith		GROUP 7616	
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EXAMINER INITIAL	CLASS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>MP</i>	AA	5,712,947	01/27/1998	<u>Oguro, et al.</u>			
<i>MP</i>	AB	6,385,389	05/07/02	<u>Maruyama, et al.</u>			
<i>MP</i>	AC	6,148,138	11/14/2000	Sawabe, et al.			
<i>MP</i>	AD	6,421,499	07/2002	Kim, et al.			
<i>MP</i>	AE	6,253,026	06/2001	Saeki, et al.			
<i>MP</i>	AF	6,389,222	05/2002	Ando, et al.			
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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>MP</i>	AG	EP 1 065 665 A1	01/03/2001	European Patent Office (in English)			
<i>MP</i>	AH	JP 5-165935	07/02/1993	JAPAN	X		
<i>MP</i>	AI	JP 5-81787	04/02/1993	JAPAN	X		
<i>MP</i>	AJ	JP 7-143429	06/02/1995	JAPAN	X		
<i>MP</i>	AK	JP 8-106721	04/23/1996	JAPAN	X		
<i>MP</i>	AL	JP 9-259539	10/03/1997	JAPAN	X		
<i>MP</i>	AM	JP 11-215471	08/06/1999	JAPAN (corresponding U.S. Patent no. 6,385,389 B1 Maruyama, et al.)			X
<i>MP</i>	AN	JP 11-238362	08/31/1999	JAPAN (corresponding European Patent No. EP 1 065 665, ANDO, et al.)			X
<i>MP</i>	AO	JP 5-158778	06/25/1993	JAPAN	X		
<i>MP</i>	AP	JP 5-165935	07/02/1993	JAPAN			X
<i>MP</i>	AQ	JP 8-205014	08/09/1996	JAPAN	X		
<i>MP</i>	AR	JP 9-182013	07/11/1997	JAPAN	X		
<i>MP</i>		JP 11-136613	05/21/1999	JAPAN	X		
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<i>MP</i>	AS	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310033 (with English translation)					
<i>MP</i>	AT	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310034 (with English translation)					
<i>MP</i>	AU	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310035 (with English translation)					
<i>MP</i>	AV	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310036 (with English translation)					
<i>MP</i>	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-310037 (with English translation)					
	AX						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <i>Huy Nguyen</i>					Date Considered <i>7/7/05</i>		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249689US2S DIV		SERIAL NO. New DIV Application	
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				FILING DATE Herewith		GROUP 2616	
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<i>HW</i>	AA	6,353,702	03/2002	Ando, et al.			
<i>HW</i>	AB	5,687,160	11/1997	Aotake, et al.			
<i>HW</i>	AC	5,731,852	03/1998	Lee			
<i>HW</i>	AD	6,185,365	02/2001	Murase, et al.			
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<i>HW</i>	AF	6,526,226	02/2003	Kashiwagi, et al.			
	AG						
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	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO			
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<i>HW</i>	AW	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2002-87033 (w/English translation)					
<i>HW</i>	AX	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1998-192063 (w/English translation)					
<i>HW</i>	AY	Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1999-256210 (w/English translation)					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>Huy Nguyen</i>				Date Considered 7/7/05			
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(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
249689US2S DIVSERIAL NO.
10/802,881

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March 18, 2004GROUP
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
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	AJ						
	AK						
	AL						
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	AN						

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		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
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	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Henry Nguyen

Date Considered

7/7/05

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